

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/593,793	XU ET AL.	
Examiner	Art Unit	
David J. Blanchard	1643	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
SEQ ID NO:113, and AA 367-375 of SEQ 113		10/16/2007	DB		

SEARCH NOT (INCLUDING SEARCH)
·	DATE	EXMR
SEQ ID NO:113, and residues 367- 375 (results in SCORE)	2/7/2007	DB
STIC search SEQ ID NO:113 and residues 367-375 (results in SCORE)	10/16/2007	DB